



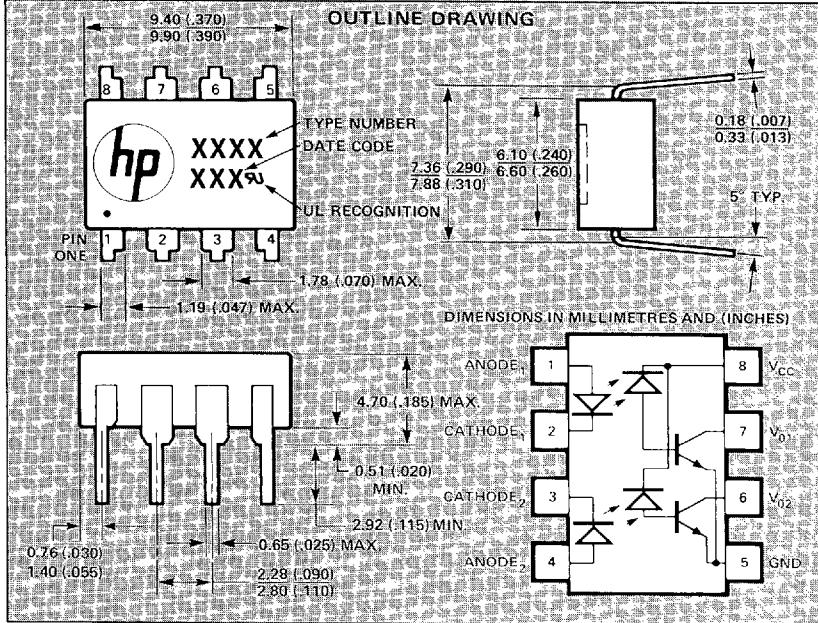
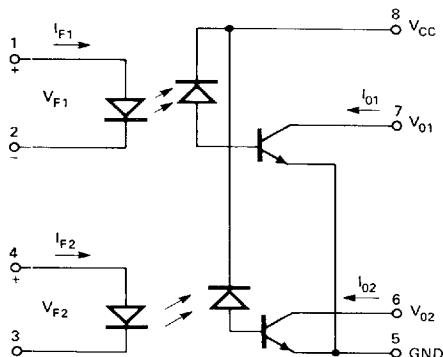
**HEWLETT
PACKARD**

DUAL LOGIC INTERFACE OPTOCOUPLER

HCPL-2533

TECHNICAL DATA DECEMBER 1981

SCHEMATIC



Features

- DATA RATES TO 250k b/s NRZ
- LSTTL COMPATIBLE
- HIGH COMMON MODE TRANSIENT IMMUNITY:
 $>1000V/\mu s$
- HIGH DENSITY PACKAGING
- 3000 Vdc WITHSTAND TEST VOLTAGE
- OPEN COLLECTION OUTPUTS
- RECOGNIZED UNDER THE COMPONENT
PROGRAM OF UNDERWRITERS
LABORATORIES, INC. (FILE NO. E55361)

Description

The HCPL-2533 is a dual channel optocoupler which is specified for use in LSTTL to LSTTL and TTL to LSTTL logic interfaces. A nominal 8 mA LSTTL sink current through the input LED will provide enough output current for proper operation of 1 LSTTL gate under worst-case conditions when used in the recommended circuits. The CTR of the HCPL-2533 is 15% minimum at $If = 8$ mA.

The HCPL-2533 contains a pair of light emitting diodes and integrated photon detectors with a 3000V dc withstand test between input and output. Separate connection for the photo-diode bias and output transistor collector reduce the base-collector capacitance, giving improved speed compared with conventional phototransistor couplers.

Applications

- HIGH SPEED LOGIC GROUND ISOLATION —
LSTTL-TO-LSTTL AND TTL-TO-LSTTL

Absolute Maximum Ratings

Storage Temperature	-55°C to +125°C
Operating Temperature	-55°C to +100°C
Lead Solder Temperature	260°C for 10s (1.6mm below seating plane)
Average Input Current — If (each channel)	25mA ^[1]
Peak Input Current — If (each channel)	50mA ^[2] (50% duty cycle, 1 ms pulse width)
Peak Transient Input Current — If (each channel)	1.0 A ($\leq 1\mu s$ pulse width, 300pps)
Reverse Input Voltage — VR (each channel)	5V
Input Power Dissipation (each channel)	45mW ^[3]
Average Output Current — Io (each channel)	8mA
Peak Output Current — Io (each channel)	16mA
Supply and Output Voltage — Vcc (Pin 8-5), Vo (Pin 7,6-5)	-0.5V to 7V
Output Power Dissipation (each channel)	35mW ^[4]

(See notes, following page.)

■ 4447584 0016823 T79 ■

Electrical Specifications, LSTTL/LSTTL

Over recommended temperature ($T_A = 0^\circ C$ to $70^\circ C$) unless otherwise specified.

Parameter	Symbol	Min.	Typ.*	Max.	Units	Test Conditions	Fig.	Note
Current Transfer Ratio	CTR	15	22		%	$I_F = 8mA, V_O = 0.5V, V_{CC} = 4.5V$ $T_A = 25^\circ C$	1	5,6
		11	15		%	$I_F = 8mA, V_O = 0.5V, V_{CC} = 4.5V$		
Logic Low Output Voltage	V _{OL}		0.2	0.5	V	$I_F = 8mA, I_O = 0.7mA,$ $V_{CC} = 4.5V$		5
Logic Low Supply Current	I _{COL}		40		μA	$I_{F1} = I_{F2} = 8mA$ $V_{O1} = V_{O2} = \text{Open}, V_{CC} = 5.5V$		
Input Forward Voltage	V _F		1.5	1.7	V	$I_F = 8mA, T_A = 25^\circ C$	2	5
Temperature Coefficient of Forward Voltage	$\frac{\Delta V_F}{\Delta T_A}$		-1.6		mV/°C	$I_F = 8mA$		5

Switching Specifications at $T_A = 25^\circ C$

$V_{CC} = 5V, I_F = 8mA, R_L = 7.5k\Omega$ unless otherwise specified.

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions	Fig.	Note
Propagation Delay Time to Logic Low at Output	t _{PHL}		0.8	1.5	μs		4,6	10
Propagation Delay Time to Logic High at Output	t _{TPLH}		1.0	2.5	μs		4,6	10
Common Mode Transient Immunity at Logic High Level Output	C _{MH}		1000		V/μs	$I_F = 0mA, V_{CM} = 10V_{p-p}$	7	9,10
Common Mode Transient Immunity at Logic Low Level Output	C _{ML}		-1000		V/μs	$V_{CM} = 10V_{p-p}$	7	9,10

Electrical Specifications, TTL/LSTTL

Over recommended temperature ($T_A = 0^\circ C$ to $70^\circ C$) unless otherwise specified.

Parameter	Symbol	Min.	Typ.*	Max.	Units	Test Conditions	Fig.	Note
Current Transfer Ratio	CTR	12	18		%	$I_F = 16mA, V_O = 0.5V,$ $V_{CC} = 4.5V, T_A = 25^\circ C$	1	5,5
		9	13		%	$I_F = 16mA, V_O = 0.5V,$ $V_{CC} = 4.5V$		
Logic Low Output Voltage	V _{OL}		0.2	0.5	V	$I_F = 16mA, I_O = 1.1mA,$ $V_{CC} = 4.5V$		5
Logic Low Supply Current	I _{COL}		80		μA	$I_{F1} = I_{F2} = 16mA$ $V_{O1} = V_{O2} = \text{Open}, V_{CC} = 5.5V$		
Input Forward Voltage	V _F		1.5	1.7	V	$I_F = 16mA, T_A = 25^\circ C$	2	5
Temperature Coefficient of Forward Voltage	$\frac{\Delta V_F}{\Delta T_A}$		-1.6		mV/°C	$I_F = 16mA$		5

Switching Specifications at $T_A = 25^\circ C$

$V_{CC} = 5V, I_F = 16mA, R_L = 4.7k\Omega$ unless otherwise specified.

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions	Fig.	Note
Propagation Delay Time to Logic Low at Output	t _{PHL}		0.3	1.5	μs		4,6	11
Propagation Delay Time to Logic High at Output	t _{TPLH}		1.1	2.5	μs		4,6	11
Common Mode Transient Immunity at Logic High Level Output	C _{MH}		1000		V/μs	$I_F = 0mA, V_{CM} = 10V_{p-p}$	7	9,11
Common Mode Transient Immunity at Logic Low Level Output	C _{ML}		-1000		V/μs	$V_{CM} = 10V_{p-p}$	7	9,11

*All typicals at $25^\circ C$.

(See following page for notes.)

Electrical Specifications

Over recommended temperature ($T_A = 0^\circ\text{C}$ to 70°C) unless otherwise specified

Parameter	Symbol	Min.	Typ.*	Max.	Units	Test Conditions	Fig.	Note
Logic High Output Current	I_{OH}	0.5	nA	50	μA	$T_A = 25^\circ\text{C}, I_F1 = I_F2 = 0\text{ mA}$ $V_{O1} = V_{O2} = V_{CC} = 5.5\text{V}$	5	5
						$I_F1 = I_F2 = 0\text{ mA}$ $V_{O1} = V_{O2} = \text{Open}, V_{CC} = 5.5\text{V}$		5
Logic High Supply Current	I_{CCH}	0.05	4	4	μA	$I_F1 = I_F2 = 0\text{ mA}$ $V_{O1} = V_{O2} = \text{Open}, V_{CC} = 5.5\text{V}$		
Input Reverse Breakdown Voltage	V_R	5			V	$I_F = 10\text{ }\mu\text{A}, T_A = 25^\circ\text{C}$		5
Input Capacitance	C_{IN}	60			pF	$f = 1\text{ MHz}, V_F = 0\text{ V}$		5
Input-Output Insulation Leakage Current	I_{I-O}			1.0	μA	45% Relative Humidity, $t = 5\text{s}$ $V_{I-O} = 3000\text{V dc}, T_A = 25^\circ\text{C}$	7	
Resistance (Input-Output)	R_{I-O}	10 ¹²			Ω	$V_{I-O} = 500\text{V dc}$		7
Capacitance (Input-Output)	C_{I-O}	0.6			pF	$f = 1\text{ MHz}$		7
Input-Input Insulation Leakage Current	I_{I-I}		0.005		μA	45% Relative Humidity, $t = 5\text{s}$ $V_{I-I} = 500\text{V dc}$	8	
Resistance (Input-Input)	R_{I-I}	10 ¹¹			Ω	$V_{I-I} = 500\text{V dc}$	8	
Capacitance (Input-Input)	C_{I-I}	0.25			pF	$f = 1\text{ MHz}$		8

Notes:

- Derate linearly above 70°C free-air temperature at a rate of $0.8\text{mA}/^\circ\text{C}$.
- Derate linearly above 70°C free-air temperature at a rate of $1.6\text{mA}/^\circ\text{C}$.
- Derate linearly above 70°C free-air temperature at a rate of $0.9\text{mW}/^\circ\text{C}$.
- Derate linearly above 70°C free-air temperature at a rate of $1.0\text{mW}/^\circ\text{C}$.
- Each channel.
- CURRENT TRANSFER RATIO is defined as the ratio of output collector current, I_O , to the forward LED input current, I_F , times 100%.
- Device considered a two-terminal device: Pins 1, 2, 3, and 4 shorted together and Pins 5, 6, 7, and 8 shorted together.
- Measured between pins 1 and 2 shorted together, and pins 3 and 4 shorted together.
- Common mode transient immunity in Logic High level is the maximum tolerable (positive) dV_{CM}/dt on the leading edge of the common mode pulse V_{CM} , to assure that the output will remain in a Logic High state (i.e., $V_O > 2.0\text{V}$). Common mode transient immunity in Logic Low level is the maximum tolerable (negative) dV_{CM}/dt on the trailing edge of the common mode pulse signal, V_{CM} , to assure that the output will remain in a Logic Low state (i.e., $V_O < 0.8\text{V}$).
- The 7.5k load represents 1 LSTTL until load of 0.36mA and a 20k Ω pull-up resistor.
- The 4.7k load represents 1 LSTTL unit load of 0.36mA and an 8.2k Ω pull-up resistor.

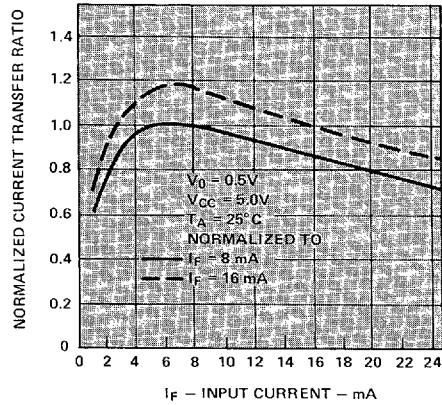


Figure 1. Current Transfer Ratio vs. Input Current

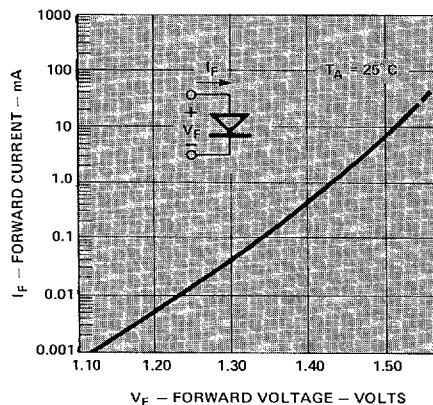


Figure 2. Input Current vs. Forward Voltage

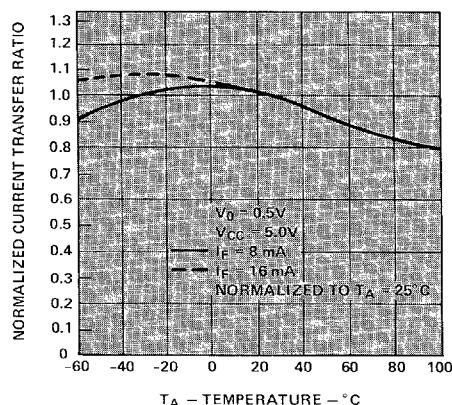


Figure 3. Current Transfer Ratio vs. Temperature

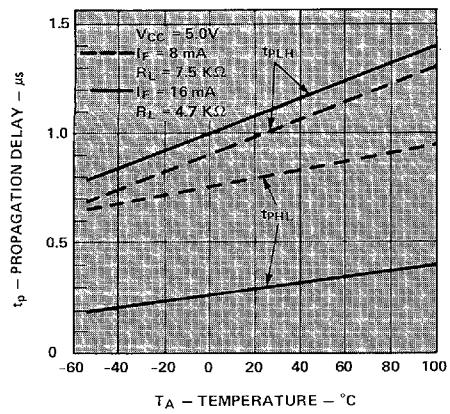


Figure 4. Propagation Delay vs. Temperature

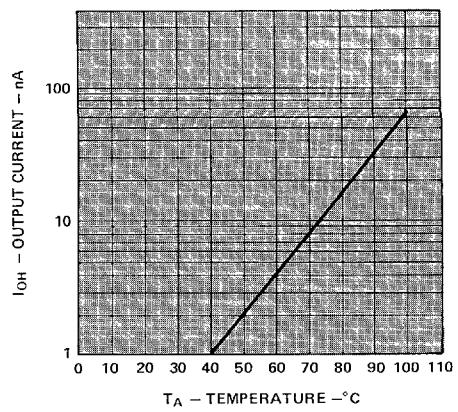


Figure 5. Logic High Output Current vs. Temperature

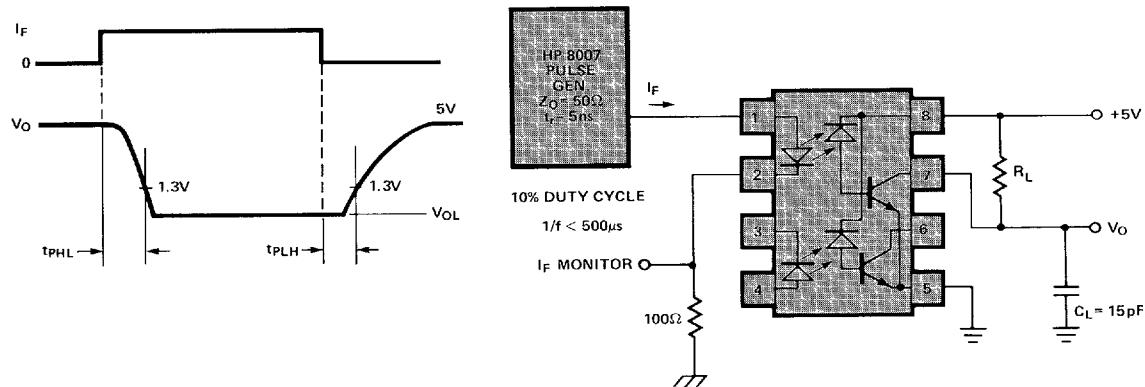


Figure 6. Switching Test Circuit

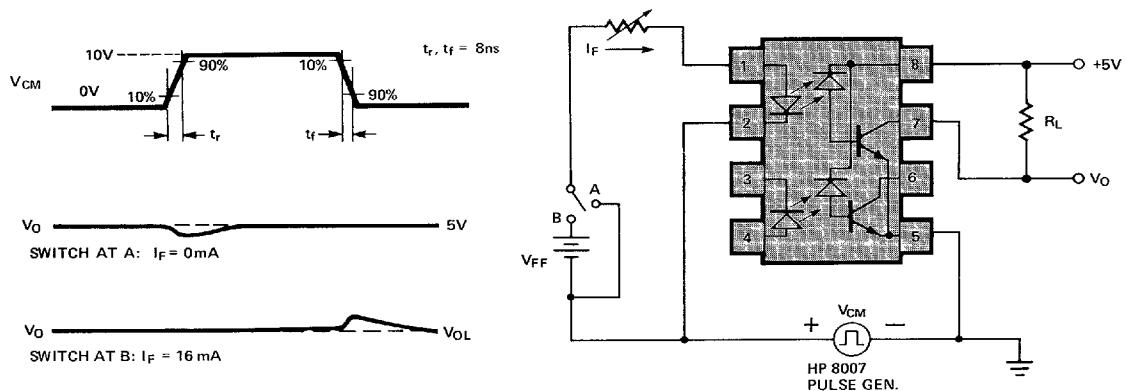
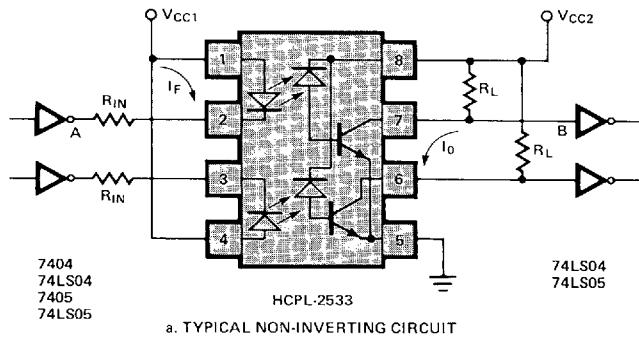


Figure 7. Test Circuit for Transient Immunity and Typical Waveforms

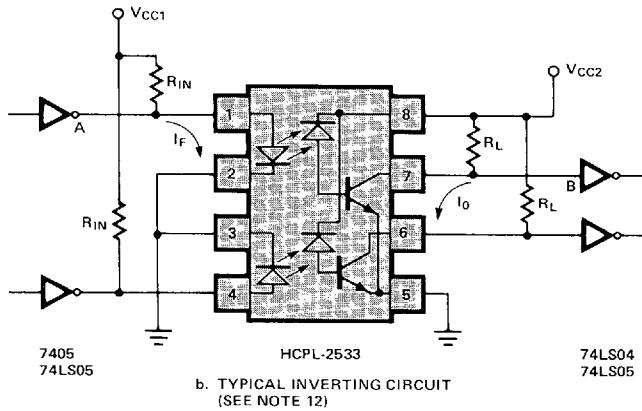
Recommended Operation

The HCPL-2533 optocoupler is specified for use in LSTTL-to-LSTTL and TTL-to-LSTTL interfaces. The recommended circuits show the interface design and give suggested component values. The input current I_F is given as both a nominal value and a range. The range in I_F results from the tolerances in V_{CC} and the input resistor R_{IN} . The CTR of the optocoupler

is given as the minimum initial value over temperature, taken directly from the Electrical Specifications. The value given for $I_{OL(min)}$ is based on the minimum CTR and the minimum I_F using worst case values for R_L and V_{CC} . The resulting $I_{OL(min)}$ has ample design margin, allowing more than 20% for CTR degradation even under these worst case conditions. For additional information on CTR degradation see Application Note 1002.



a. TYPICAL NON-INVERTING CIRCUIT



b. TYPICAL INVERTING CIRCUIT
(SEE NOTE 12)

Figure 8. Recommended Circuits

Recommended Circuit Design Parameters

Parameter	Symbol	LSTTL to LSTTL	TTL to LSTTL	Units	Comments	Fig.	Note
INPUT							
Logic Low Output Voltage — Input Gate	$V_{OL(A)}$	0.5	0.4	V	Maximum		
Supply Voltage — Input	V_{CC1}	5.0	5.0	V	+5%		
Input Resistor	R_{IN}	360	180	Ω	+5%	8a	
		430	200	Ω	-5%	8b	
Input Current	I_F	8	16	mA	Nominal		
Input Current Range	I_F	6.75—10	14.0—20	mA		8a	
			14.5—20	mA		8b	
OUTPUT							
Logic Low Output Voltage — HCPL-2533	$V_{OL(B)}$	0.5	0.5	V	Maximum		
Supply Voltage — Output	V_{CC2}	5.0	5.0	V	+5%		
Pull-Up Resistor	R_L	20	8.2	$k\Omega$	+5%		13
Required Current Sink for Logic Low	$I_{OL(max)}$	0.61	1.0	mA	$I_{OL(max)} = I_{OL(B)(max)} + I_R(max)$		14
HCPL-2533 Current Transfer Ratio	CTR	11	9	%	Minimum $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$		
Logic Low Output Current — HCPL-2533 (min)	$I_{OL(min)}$	0.74	1.26	mA	Worst Case V_{CC} , R_L , $I_{OL(B)}$, $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$	8a	15
Data Rate	f_D	250	250	Kb/s	NRZ, $T_A = 25^\circ\text{C}$		16

Notes:

12. The inverting circuit has higher power consumption and must use open collector gates on the input.
13. The load resistor R_L must be large enough to guarantee logic LOW and small enough to guarantee logic HIGH under worst case conditions:
14. The maximum current sink required for logic LOW is:

$$I_{OL(max)} = I_{OL(B)(max)} + I_R(max)$$
 where I_R is the current through R_L .
15. The ratio of $I_{OL(min)}$ to $I_{OL(max)}$ gives the design margin for CTR degradation. See Application Note 1002.
16. The maximum data rate is defined as

$$\frac{V_{CC(max)} - V_{OL}}{I_{OL(2533)} - I_{OL(B)}} \leq R_L \leq \frac{V_{CC(min)} - V_{IH(B)}}{I_{OH(2533)} - I_{IH(B)}}$$

The selection of R_L is the same for both inverting and non-inverting circuits.

$$f_D = \frac{1}{t_{PHL} + t_{PLH}} \text{ bits/second NRZ}$$